

P-Type Silicon p-i-n Photodetector

- Wide Range of Operating Voltage -0 to 90 volts
- **Anti-Reflection Coated to Enhance** Responsivity at 900 nm
- **Hermetically-Sealed Package**
- Spectral Response Range -(10% points) 400 to 1100 nm

RCA Developmental Type C30900E is a p-type silicon p-i-n photodiode designed for use in a variety of broadband low light level applications covering the spectral from about 400 to 1100 nanometers.

This device has a hermetically-sealed package and incorporates a guard ring in its structure to minimize surface leakage current.

The C30900E may be operated satisfactorily over a wide range of applied voltage with capacitance, speed of response, and dark current being functions of applied operating volt-

The C30900E is anti-reflection coated to enhance its responsivity at 900 nm making the device highly useful for GaAs and HeNe laser detection as well as for optical communication and intrusion alarm systems.

Maximum Ratings,

Absolute-Maximum Values		
DC Reverse Operating Voltage, VR	200	max. V
Photocurrent Density, jp, at 22° C:		•
Average value, continuous operation	5	mA/mm ²
Peak value	20	mA/mm ²
Forward Current, I F:		
Average value, continuous operation	10	max, mA
Peak value	100	max, mA
Maximum Total Power Dissipation at 22° C	0.5	max. W
Ambient Temperature:		···urii VI
Storage, T _{stg} 60 to +	100	оС
Operating, T _A 40 to	+80	οс
Soldering:		
For 5 seconds	200	oC

Mechanical Characteristics

Photosensitive Surface:

Shape	Çit	rcular
Area	5	mm ²
Diameter		

Optical Characteristics

Field of View:a (See Figure 5)

Full angle (α) for totally illuminated photosensitive surface	70	dea
Full angle (a') for partially		3
illuminated photosensitive surface	120	dea

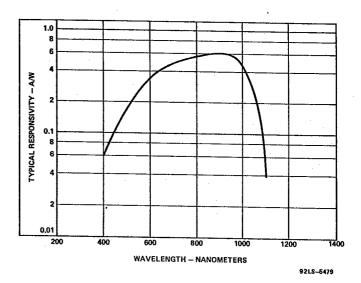
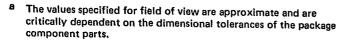


Figure 1 — Typical Spectral Responsivity Characteristic

For further information or application assistance on these devices, contact your RCA Sales Representative or Photodetector Marketing, RCA, Ste. Anne de Bellevue, Quebec, Canada H9X 3L3 (514) 457-9000.

C30900E

Electrical Characteristics at TA = 22° C	At V _R = 90 volts ^b , unless otherwise specified.			Units	
Breakdown Voltage,	Min.	Тур.	Max.		
VBR	-	150	_	V	
At 900 nm	0.5	0.6		A/W	
Quantum Efficiency:					
At 900 nm	70	83	· ·	%	
Dark Current, Id:					
At $V_R = 10 \text{ V} \dots$	-	1x10 ⁻⁸	5x10 ⁻⁸	Α	
At V _R = 90 V	_	1×10 ⁻⁷	1.5×10 ⁻⁷	Α	
Noise Current, in:	·				
f = 1000 Hz, △f = 1.0 Hz See Figure 3	_	3×10-13	7×10 ⁻¹³	A/Hz1/2	
Noise Equivalent Power (NEP):			:		
f = 1000 Hz, △f = 1.0 Hz					
At 900 nm	-	5x10-13	1.4x10-12	W/Hz1/2	
Capacitance, C _d See Figure 4	-	5	7	pF	
Channel Resistance	1	_		мΩ	
Rise Time, t _r :					
R _L = 50 Ω , λ = 900 nm, 10% to 90% points	_	6	10	ns	
Fall Time:				119	
R _L = 50 Ω , λ = 900 nm, 90% to 10% points	_	7	25	ns	



b The recommended reverse operating voltage V_R at T_A = 220 C is 90 volts. However, when the devices are operated in the photovoltaic mode, i.e., at $V_R = 0$ volts, some of the electrical characteristics will differ from those shown.

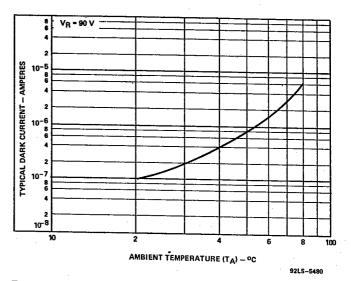


Figure 2 — Typical Dark Current vs Ambient Temperature

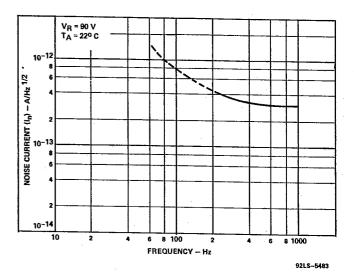
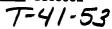


Figure 3 - Typical Noise Current vs Frequency



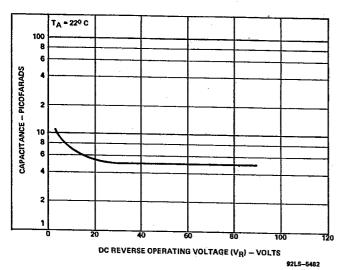
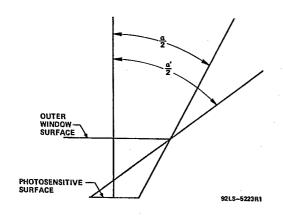


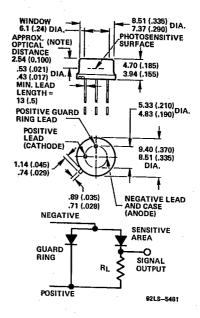
Figure 4 — Typical Photodetector Capacitance vs **Operating Voltage**



For incident radiation at angles $\leq \frac{a}{2}$, the photosensitive surface is

For incident radiation at angles $> \frac{a}{2}$ but $\leq \frac{a'}{2}$, the photosensitive surface is partially illuminated.

Figure 5 — Definition of Half-Angle Approx. Field-of-View. (Scale is exaggerated for clarity)



Low-Profile TO-5 Package

Dimensions in millimeters. Dimensions in parentheses are in inches.

Note: Optical distance is defined as the distance from the surface of the silicon chip to the front surface of the window.

Figure 6 — Dimensional Outline